



STS Directory

Accreditation number: STS 0591

International standard: ISO/IEC 17025:2017
Swiss standard: SN EN ISO/IEC 17025:2018

Helmut Fischer AG
Moosmattstrasse 1
6331 Hünenberg

Head: Michael Schwarzenberger
Responsible for MS: Michael Schwarzenberger
Telephone: +41 41 785 08 30
E-Mail: michael.schwarzenberger@helmut-fischer.com
Internet: www.helmut-fischer.ch
Initial accreditation: 09.12.2013
Current accreditation: 09.12.2023 to 08.12.2028
Scope of accreditation see: www.sas.admin.ch
(Accredited bodies)

Scope of accreditation as of 09.12.2023

Testing laboratory for length measurements, coating thickness measurements, elemental analysis and electrical conductivity measurements

Group of products or materials, field of activity	Principle of measurement ²⁾ (characteristics, measuring ranges, type of test)	Test methods, remarks (national, international standards, in-house test methods)
Coating thickness measurements of various coated materials (Galvanized, anodized, painted materials, PVD, CVD coating structures etc.)	Microscopic methods Evaluation of ion-beam polished cross-sections with scanning electron microscopy Measuring range: 0.5 - 500 micrometer (µm) Electromagnetic measurement methods (Magnetic induction method, amplitude- or phase-sensitive eddy-current methods) Measuring range: ca. 0.1 µm – 100 mm (mm)	Modified according to: SN EN ISO 9220 SN EN ISO 1463 Internal method: F1188 ISO 2178 ISO 2360 ISO 21968



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Group of products or materials, field of activity	Principle of measurement ²⁾ (characteristics, measuring ranges, type of test)	Test methods, remarks (national, international standards, in-house test methods)
Coating thickness measurements of various coated materials (Galvanized, anodized, painted materials, PVD, CVD coating structures etc.)	X-ray fluorescence spectroscopy, (ED-XRF) Measuring range: 5 nanometers (nm) – 100 µm	ISO 3497
Elemental analysis of solid materials and solutions (Bulk material, coating material, powder)	X-ray fluorescence spectroscopy (ED-XRF) Measuring range: ~10 mg/kg – 1000 g/kg, depending on analyte/matrix	ISO 3497
	Inductively coupled plasma optical emission spectroscopy (ICP-OES) Measuring range: ~10 mg/kg – 1000 g/kg, depending on analyte/matrix	ISO 11885
Electrical conductivity measurement of non-ferrous metals	Phase-sensitive eddy-current measurement Measuring range 0.3 - 60 MS/m	DIN EN 2004-1
Measurement of mechanical properties of bulk materials, coatings, etc. (Martens hardness, indentation modulus)	Instrumented indentation test Measuring range: Load range: 0.05 – 2000 mN Hardness range: < diamond Indenter: Vickers, Berkovich, semi-spheres	Modified according to: ISO 14577 internal Method: F1190

In case of contradictions in the language versions of the directories, the German version shall apply.

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